# CIS 4930 Digital System Testing Testing for Single Stuck-at Faults (SSFs) 

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## Testing Generation

Testing Generation (TG) is a complex problem We are interested in:
$\rightarrow$ The cost of generating the test
$\rightarrow$ The quality (fault coverage) of the test
$\rightarrow$ The cost of applying the test

## Types of Test Generation

Test Generation

Deterministic


## Manual Automatic



Fault Oriented
Fault Independent

## Deterministic TG System



Figure 6.1 Deterministic test generation system

### 6.2.1 Fault-oriented ATG

$\rightarrow$ Circuit model - gate-level combinational circuit
$\rightarrow$ Basic Algorithm - Fanout Free
$\rightarrow$ Backtracking Algorithm
$\rightarrow$ D Algorithm
$\rightarrow$ PODEM (Path Oriented Decision Making)
$\rightarrow$

## Line Justification

$\rightarrow$ To detect a fault
$\rightarrow$ Activate the fault
$\rightarrow$ Propagate the fault to a PO

Activating a fault a $l s-a-v$ :
$\rightarrow$ Determine PI values that force value on line $l$ to $\bar{v}$

This is known as the line-justification problem

## Composite Logic Values

## Let $D$ represent $1 / 0$ and $\bar{D}$ represent $0 / 1$

| $\mathbf{v} / \mathbf{v}_{\boldsymbol{f}}$ |  |
| :---: | :---: |
| $0 / 0$ | 0 |
| $1 / 1$ | 1 |
| $1 / 0$ | $\boldsymbol{D}$ |
| $0 / 1$ | $\overline{\boldsymbol{D}}$ |


| AND | $\mathbf{0}$ | $\mathbf{1}$ | $\mathbf{D}$ | $\overline{\mathbf{D}}$ | $\mathbf{X}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathbf{0}$ | 0 | 0 | 0 | O | O |
| $\mathbf{1}$ | 0 | 1 | D | $\overline{\mathbf{D}}$ | X |
| $\mathbf{D}$ | 0 | D | D | O | X |
| $\overline{\mathbf{D}}$ | 0 | $\mathrm{D}^{\prime}$ | O | $\overline{\mathbf{D}}$ | X |
| $\mathbf{X}$ | 0 | X | X | X | X |


| $\mathbf{O R}$ | $\mathbf{0}$ | $\mathbf{1}$ | $\mathbf{D}$ | $\overline{\mathbf{D}}$ | $\mathbf{x}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathbf{0}$ | 0 | 1 | D | $\mathrm{D}^{\prime}$ | O |
| $\mathbf{1}$ | 1 | 1 | 1 | 1 | 1 |
| $\mathbf{D}$ | D | 1 | D | 1 | X |
| $\overline{\mathbf{D}}$ | $\overline{\mathbf{D}}$ | 1 | 1 | $\overline{\mathbf{D}}$ | X |
| $\mathbf{X}$ | X | 1 | X | X | X |

## Fig 6.3 TG for I $s-a-v$ in Fanout Free circuit

## begin set all values to $x / /$ initialization of all wires to X <br> Justify (l, $\bar{v}$ ) //justification of line / if $v=0$ then Propagate ( $l, D$ ) else Propagate ( $l, \bar{D}$ ) <br> end

## Line Justification



Justify (l, val) begin
set $l$ to val
if $l$ is a PI then return /* $l$ is a gate (output) */
$c=$ controlling value of $l$
$i=$ inversion of $l$
inval $=v a @ i$
if (inval $=\bar{c}$ )
then for every input $j$ of $l$
Justify (j, inval)
else

## begin

select one input $(j)$ of $l$
Justify (j, inval)
end
end

## Error Propagation - Fanout Free circuit

Propagate (l, err) /*err is $D$ or $\bar{D}$ */

## begin

set $l$ to $e r r$
if $l$ is PO then return
$k=$ the fanout of $l$

$c=$ controlling value of $k$
$i=$ inversion of $k$
for every input $j$ of $k$ other than $l$
Justify ( $j, \bar{c}$ )
Propagate $(k$, err $\oplus i)$
end

## Example 6.1



Find an input vector such that $f s-a-0$ is observable on $j$

## Example 6.1



## Example 6.1



## Example 6.1

## Propagate ( $f$, D)



## Example 6.1

Propagate (h, D)


## Example 6.1

## Propagate (j, D)



## Example 6.1



## Fanout Free vs. Fanout

$\rightarrow$ For Fanout Free circuit
$\rightarrow$ Line justification problems are independent
$\rightarrow$ Sets of Pl's assigned to justify required values are mutually disjoint
$\rightarrow$ Circuits with Fanout
$\rightarrow$ Several ways to propagate error to PO
$\rightarrow$ Fundamental difficulty: see following examples resulting line justification problems are no longer independent

## Example 6.2



## Example 6.2



## Example 6.2



## Example 6.2



## Example 6.2



## Example 6.2



## Example 6.2



## Backtracking Strategy

$\rightarrow$ Search for a test vector $\rightarrow$ decision process
$\rightarrow$ Several alternatives for a line justification problem
$\rightarrow$ Pick one alternative
$\rightarrow$ If it leads to an inconsistency, then backtrack!
$\rightarrow$ Backtracking Strategy
$\rightarrow$ Systematic exploration
$\rightarrow$ Recovery from incorrect decisions

- Invert all values assigned since last decision


## Example 6.3



## Example 6.3



## Example 6.3



## Example 6.3



## Example 6.3



## Example 6.3



## Example 6.3



## Example 6.3



Decision: choose one alternative if there are multiple alternatives to justify() or propagate()

Implication: compute new values as a result of decision, and check inconsistencies.

| Decisions | Implications | Remarks |
| :---: | :---: | :---: |
|  | $\begin{gathered} \mathrm{h}=\mathrm{D}^{\prime} \\ \mathrm{e}=1 \\ \mathrm{f}=1 \\ \mathrm{p}=\mathrm{D}^{\prime} \\ \mathrm{r}=1 \\ \mathrm{q}=1 \\ \mathrm{o}=0 \\ \mathrm{~s}=\mathrm{D}^{\prime} \end{gathered}$ | Initial Implications |
| $l=1$ | $\begin{aligned} \mathrm{c} & =1 \\ \mathrm{~d} & =1 \\ \mathrm{~m} & =0 \\ \mathrm{n} & =0 \\ \mathrm{r} & =0 \end{aligned}$ | To justify $q=1$ <br> Contradiction |
| $k=1$ | $\begin{aligned} & a=1 \\ & b=1 \end{aligned}$ | To justify $\mathrm{q}=1$ |
| $\mathrm{m}=1$ | $\begin{aligned} & \mathrm{c}=0 \\ & l=0 \end{aligned}$ | To justify r=1 |

## Fig 6.10 TG Algorithm Outline

Solve()
begin
if Imply_and_check() = FAILURE then return FAILURE
if (error at PO and all lines are justified) then return SUCCESS
if (no error can be propagated to a PO) then return FAILURE
select an unsolved problem
repeat
begin
select one untried way to solve it
if Solve() = SUCCESS then return SUCCESS
end
until all ways to solve it have been tried return FAILURE
end
6.2 ATG for SSFs in Combinational Circuits

## Decision Tree


(b)

## TG Failure for an Undetectable Fault

$\rightarrow$ Solve() is exhaustive - guarantee to find a test if one exists.
$\rightarrow$ worst case complexity is exponential


Figure 6.12 TG failure for an undetectable fault (a) Circuit (b) Decision tree

## D-Frontier

$\rightarrow$ D-frontier - all gates whose output value is currently $x$ but have one or more error signals on their inputs.
$\rightarrow$ D-drive operation -
Pick a gate and try to propagate error

$\rightarrow$ If $\boldsymbol{D}$-frontier becomes empty
$\Rightarrow$ No error can be propagated to PO
$\Rightarrow$ Backtracking should occur

Gates in D-frontier indicate necessary decisions in order to proceed.

## J-Frontier

$\rightarrow$ J-frontier - all gates whose output value is known, but not implied by its input values
$\rightarrow$ Helps keep track of currently unsolved linejustification problems


All inputs are implied to be 1.


No implications on x-inputs.

## Implication Process

3 Steps:

1. Compute all values that can be uniquely determined by implication
2. Check for consistency and assign values
3. Maintain the D-frontier and J-frontier

Implication can be forward or backward.

## Backward Implication Propagation

## Before


(d)

## Forward Implication Propagation

Figure 6.15


## Forward Implication Propagation



## Forward Implication Propagation - cont'd

Before

$D$-frontier $=\{\ldots, a\}$

After
(a)
(b)
(c)
$\bar{D} \square 0 \rightarrow 0$-frontier $=\{\ldots\}$


D-frontier $=\{\ldots\}$

(d)

Figure 6.16

## Figure 6.17 Unique D-Drive

$\rightarrow$ When only gate remains in the $D$-frontier. $\rightarrow$ There is only one way to propagate $D$.

Before



After
$D$-frontier $=\{a\}$


## Figure 6.18 Future Unique D-drive

- $D$-frontier $=\{\mathrm{d}, \mathrm{e}\}$
- Eventually we end up unique $D$-drive with gate $g$ only


This type of propagations is global implication.

## Reversing Incorrect Decisions

$\rightarrow$ Assume that $a=0$ failed irrespective of $b$ and $c$ $\Rightarrow a$ must be 1 !


Figure 6.21 Reversing incorrect decisions

## Look-Ahead in Error Propagation

$\rightarrow$ No matter how we propagate, D-frontier will be empty!
$\rightarrow$ Look-ahead: Error propagation is possible only if there is at least one $x$-path from gate $G$ in $D$-frontier to at least one PO. (a necessary condition)
$\rightarrow X$-paths used to avoid failed decisions.


## D-Algorithm

$\rightarrow$ Ability to propagate errors on several reconvergent fanouts
$\rightarrow$ We assume error propagation is given priority over justification problems (simplifying assumption)
$\rightarrow$ "assign" means "add the value to the assignment queue"
$\rightarrow$ Imply_and_check() handles the assignments

1. $D-a \lg ()$
2. begin
3. if Imply_and_check() = FAIL then return FAIL
4. if (error not at PO) then /* error propagation */
5. begin
6. 
7. 
8. 
9. 
10. 
11. 
12. 
13. 
14. 
15. 
16. end
17. /* error propagated to a PO */
18. if $J$-frontier $=\varnothing$ then return SUCCESS
19. select a gate (G) from the J-frontier
20. $c=$ controlling value of G
21. repeat
22. begin
23. select an input ( $j$ ) of $G$ with value $x$
24. assign $c$ to $j$
25. 
26. 
27. end
28. until all inputs of G are specified
29. return FAIL
30. end


Example 6.6
6.2.1.2 Algorithms

Example 6.6


Example 6.6



| Decisions $\quad$ Implications



Each node is a D-frontier.

## PODEM - Path Oriented Decision Making

$\rightarrow$ Direct search process
$\rightarrow$ Decisions only about PI assignments.
$\rightarrow$ In D-algorithm, decisions on PIs are indirect.
$\rightarrow$ Value $v_{k}$ to be justified on line $k$
$=$ Objective ( $k, v_{k}$ ) to achieve via PI assignments.
$\rightarrow$ Backtracing of an objective
$\rightarrow$ Maps a desired objective into a PI assignment
$\rightarrow$ Note that no values are assigned during backtracing

Backtrace (k, $v_{k}$ )
/* map objective into PI assignment */
begin

$$
v=v_{k}
$$

while $k$ is a gate output // Recursive generating
begin // objectives until it reaches PI
$i=$ inversion of $k$ select an input ( $j$ ) of $k$ with value $x$ $v=v \oplus i$
$k=j$
end
${ }^{*} k$ is a $\mathrm{PI} * /$
return $(k, v)$
end

## Backtrace - An Example



- Objective (f, 1)

Figure 6.28

- First Backtrace $(f, 1)$ call:
- Path $(f, d, b)$ is tried with $b=1$ as PI assignment
- But $b=1$ is not enough to achieve objective $(f, 1)$
- Second Backtrace ( $f, 1$ ) call:
- Path $(f, d, c, a)$ is tried with $\mathrm{a}=0$
- Now with a=0, we can achieve objective ( $f, 1$ )


## Selecting an Objective

Objective()
begin

## Activate fault

/* the target fault is $l s-a-v * /$
if (the value of $l$ is $x$ ) then return $(l, \bar{v})$ select a gate $(G)$ from the $D$-frontier select an input $(j)$ of $G$ with value $x$ $c=$ controlling value of $G$
]

Find the
necessary inputs to return $(j, \bar{c})$
end

```
PODEM() // All lines are initialized to x
begin
    if (error at PO) then return SUCCESS
    if (test not possible) then return FAILURE
    (k,vk})=\mathrm{ Objective()
    (j,v}\mp@subsup{)}{}{\prime}=\operatorname{Backtrace}(k,\mp@subsup{v}{k}{})/*j\mathrm{ is a PI */
    Imply (j,v v})///5\mathrm{ -value simulation with PI assignments
    if PODEM() = SUCCESS then return SUCCESS
    /* reverse decision */
    Imply (j,\mp@subsup{\overline{v}}{j}{})
    if PODEM() = SUCCESS then return SUCCESS
    Imply (j,x)
    return FAILURE // D-frontier becomes empty
end
```


6.2.1.2 Algorithms




| Objective | PI Assignment | Implications | D-frontier |  |
| :---: | :---: | :---: | :---: | :---: |
| $a=0$ | $a=0$ | $h=1$ | $g$ |  |
| $b=1$ | $b=1$ |  | $g$ |  |
| $c=1$ | $c=1$ | $g=D$ | $i, k, m$ |  |
| $d=1$ | $d=1$ | $\begin{gathered} d^{\prime}=0 \\ i=\bar{D} \end{gathered}$ | $k, m, n$ |  |
| $k=1$ | $e=0$ | $\begin{gathered} e^{\prime}=1 \\ j=0 \\ k=1 \\ n=1 \end{gathered}$ | $m$ | $x$-path check fails |
|  | $e=1$ | $\begin{gathered} e^{\prime}=0 \\ j=1 \\ k=\bar{D} \\ n=x \end{gathered}$ | $m, n$ | reversal |
| $l=1$ | $f=1$ | $\begin{gathered} f^{\prime}=0 \\ l=1 \\ m=\bar{D} \\ n=D \end{gathered}$ |  |  |



## D-Algorithm vs PODEM

$\rightarrow$ PODEM does not need
$\rightarrow$ Consistency check
$\rightarrow$ J-frontier
$\rightarrow$ Backward implication propagation
$\rightarrow$ Backtracking in PODEM is more simplified. $\rightarrow$ Overall, PODEM is more efficient.

## Selection Criteria

$\rightarrow$ Search process involves decisions
$\rightarrow$ Decisions on how to:
$\rightarrow$ Select one of several unsolved problems: fault propagation/line justification.
$\rightarrow$ Select one possible way to solved the selected problem: several possible inputs to justify output 0 of AND gate.

What are the selection criteria?
Some principles to speed up the search process.

## Selection Criteria - Principles

$\rightarrow$ Among different unsolved problems, first attack the most difficult one
$\rightarrow$ Thus avoid useless time spent in solving the easier problems when a harder one cannot be solved
$\rightarrow$ Among different solutions of a problem, first try the easiest one
$\rightarrow$ Difficulty is measured by cost functions.

## Cost Functions

$\rightarrow$ Controllability measures
$\rightarrow$ Related to the Line Justification problem
$\rightarrow$ Relative difficulty of setting a line to a value
Ex: select most difficult line-justification problem
$\rightarrow$ Observability measures
$\rightarrow$ Related to the Error Propagation problem
$\rightarrow$ Relative difficulty of propagating an error from a line to a PO
Ex: select the gate from $D$-frontier whose input error is easiest to observe
Important: Must be relative measures and easy to compute.

## Distance Based Cost Functions

$\rightarrow$ Any cost function should show that
$\rightarrow$ Pls are the easiest to control
$\rightarrow$ POs are the easiest to observe
$\rightarrow$ Therefore
$\rightarrow$ Difficulty of controlling a line increases with its distance from Pls
$\Rightarrow$ Line Level can be used as a controllability measure!
$\rightarrow$ Difficulty of observing a line increases with its distance from POs
$\Rightarrow$ Shortest distance of a line to PO can be used as a observability measure!
Main Drawback: Does not take into account the logic function

## Controllability Measure C(l)

For every signal we want to compute:
$C O(l)=$ Relative difficulty of setting line $l$ to 0
C1 $(l)=$ Relative difficulty of setting line $l$ to 1
Assume we know C0 and C1 costs of all inputs of the AND gate, To set $X$ to 0 :
$\mathrm{CO}(\mathrm{X})=\min \{\mathrm{CO}(\mathrm{A}), \mathrm{CO}(\mathrm{B}), \mathrm{CO}(\mathrm{C})\}$
To set $X$ to 1:
$C 1(X)=C 1(A)+C 2(B)+C 3(C)$
assuming $A, B, C$ are independent (i.e., do not depend on common Pls)
We can develop similar cost functions for other gates. OR gate?

## Controllability Measure Computation

$\rightarrow$ Set CO and C1 for every primary input to 1
$\rightarrow$ Compute CO's and C1' level by level
$\rightarrow$ Cost are computed only after predecessor costs are known
$\rightarrow$ Costs can be computed in one forward traversal
$\rightarrow$ Linear in number of gates

## Issues

If inputs of a gate are not independent, it can lead to incorrect results
In (a) cost of controlling $B$ and $C$ is the same
In (b) B and C cannot be set to 1 simultaneously, so $C 1(X)$ should show that setting $X=1$ is impossible


## Observability Measure $O(l)$

Cost of observing the input A ?
$\rightarrow$ We must set B and C to 1
$\rightarrow$ Propagate error from $X$ to a PO


$$
O(A)=C 1(B)+C 1(C)+O(X) \ldots \quad E q(3)
$$

Assuming controlling $B=1, C=1$, and propagating $\mathrm{Err}(\mathrm{X})$ to PO are independent problems

What about OR gate?

## Observability of a Stem X


$O(X)=\min \{O(X 1), O(X 2), O(X 3)\} \quad .$. Eq (4) Assuming single path propagation is possible

## Observability Measure Computation

$\rightarrow$ Set observability cost of every PO to 0
$\rightarrow$ Compute observabilities level by level backward manner using eq 3 and 4 .
$\rightarrow$ Cost are computed only after successor costs are known
$\rightarrow$ Costs can be computed in one backward traversal
$\rightarrow$ Linear in number of lines
$\rightarrow$ Assume controllability measure is known.

## Fanout-Based Cost Functions

$\rightarrow$ Reconvergent fanout makes TG difficult.
$\rightarrow$ A line with fanout has high potential causing conflict.


Setting $B=0$ is better than $A=0$


## Fanout-Based Controllability Measure

$\rightarrow \mathrm{C}(l)$ depends on
$\rightarrow$ Fanout count of $l$
$\rightarrow$ Fanout count of predecessors of $l$

$$
\begin{equation*}
C(l)=\sum_{i} C(i)+f_{l}-1 \tag{6.5}
\end{equation*}
$$

Where $f_{l}$ is the fanout count of $l$

A line $/$ with $C(I)=0$ means it does not depend on any fanout lines.

## Example

$$
C(l)=\sum_{i} C(i)+f_{l}-1
$$

$C(A)=0$
$C(B)=2$
$C(X)=2$
Therefore, select $A=0$ to justify $\mathrm{X}=0$.


## C0(l) and C1(l) - More Accurate Cost Func.

$\rightarrow E q(6.5)$ does not distinguish between setting a line to 0 and to 1

For the AND gate we have:

$$
C O(l)=\min \{C O(i)\}+f_{l}-1
$$

and

$$
C 1(l)=\sum_{i} C 1(i)+f_{l}-1
$$

What about OR gàte?

## Example

$$
\begin{aligned}
& \mathrm{CO}(l)=\min \{\mathrm{CO}(i)\}+f_{l}-1 \\
& C(l)=\sum_{i} C(i)+f_{l}-1
\end{aligned}
$$

$\mathrm{CO}(\mathrm{A})=\mathrm{C1}(\mathrm{~A})=1$
$\mathrm{CO}(\mathrm{B})=\mathrm{C1}(\mathrm{~B})=0$
$\mathrm{CO}(\mathrm{X})=0$,
$C 1(X)=1$.


## Side Effects - Example



- $\mathrm{CO}(\mathrm{A})$ and $\mathrm{C1}(\mathrm{~A})$ both have corrective terms $=1$
- $A=0$ has greater potential of conflicts than $A=1$
- $A=0$ results in $B, C, D, E$ being set to binary values
- Less $x$-paths for error propagation.


## Side Effects Cost Function

$\rightarrow$ Side-Effects Cost Functions: $\operatorname{CSO}(l)$ and $\operatorname{CS1}(l)$ to account for relative potential for conflicts caused by setting $l$ to 0 and 1
$\rightarrow$ Computed by simulating $l=v(v \in\{0,1\})$ in a circuit initialized with all- $x$ state, and then
$\rightarrow$ A gate whose output is set to a binary value increases cost by 1
$\rightarrow$ A gate with $n$ inputs whose output remains at $x$ but which has $m$ inputs set to a binary value, increases the cost by $m / n$

## Side Effect Function - Example



- $\operatorname{CSO}(\mathrm{A})=4(1 / 2)$
- $\operatorname{CS1}(\mathrm{A})=(1 / 3)+(1 / 2)=5 / 6$


## Cost Functions with Side-Effects

$$
\begin{aligned}
& \mathrm{CO}(l)=\min \{\mathrm{CO}(i)\}+\operatorname{CSO}(l) \\
& C 1(l)=\sum_{i} C 1(i)+\operatorname{CS1}(l)
\end{aligned}
$$

- Require circuit simulation after assigning / to 0 or 1
- Cause additional complexity


## Cost Functions: Summary

$\rightarrow$ Complexity of cost function computation must be low.
$\rightarrow$ Cost functions are based heuristics.
$\rightarrow$ Dynamic cost functions may lead to better performance.

## Backup

## Fault Independent ATG

$\rightarrow$ Fault-oriented algorithm targets a given fault and generate a test vector
$\rightarrow$ Fault-independent algorithm's goal:
$\rightarrow$ Derive a set of test that detect a large set of SSFs w/o targeting individual faults
$\rightarrow$ CPT -- Half of the SSFs on a path critical in a test $t$ are detected by $t$
$\Rightarrow$ Generate tests that produce long critical paths
$\Rightarrow$ Critical path TG algorithm

## Critical Paths - Basic Concept



The input vector detects output s-a-0 fault and other faults on the critical nath

## Critical-path TG Algorithm

Basic Steps

1. Select a PO and assign it a critical 0-value or 1value (Recall that a PO is always critical)
2. Recursively justify the PO value, trying to justify any critical value on a gate output by critical values on the gate inputs

## Line Justification - 3 Input AND gate

By Primitive Cubes

| $A$ | $B$ | $C$ | $Z$ |
| :--- | :--- | :--- | :--- |
| 1 | 1 | 1 | 1 |
| 0 | $x$ | $x$ | 0 |
| $x$ | 0 | $x$ | 0 |
| $x$ | $x$ | 0 | 0 |

(a)

By Critical Cubes

(b)

## Critical-path TG - Example



What SSFs can be detected by this input vector?

## Critical-path TG - Example ...contd.


(c)


(d)


```
CPTGFF()
begin
    while (Critical # \varnothing)
    begin
        remove one entry (l,val) from Critical
        set l to val
        mark l as critical
        if l is a gate output then
            begin
                c= controlling value of l
                    i= inversion of l
                            inval = val }\oplus
                            if (inval =
                            then for every input j of l
                                add (j,\overline{c}) to Critical
                            else
                                begin
                            for every input j of l
                                    begin
                                    add (j,c) to Critical
                                    for every input }k\mathrm{ of l other than j
                                    Justify (k,\overline{c}
                                    CPTGFF()
                                    end
                                    return
                                end
            end
        end
    /* Critical = \varnothing */
    record new test
    return
end
```


## Decision Tree



Figure 6.47 Decision trees for Example 6.12
The number of terminal nodes equals the number of tests generated ${ }_{i 01}$

## ATG for SSFs in Sequential Circuits

$\rightarrow$ TG using Iterative Array Model
$\rightarrow$ Extends TG methods of combinational circuits to sequential circuits
$\rightarrow$ Transform Synchronous sequential circuit into an iterative combinational array.
$\rightarrow$ Unroll the circuit for $k$ times.
$\rightarrow$ One cell in the array -> time frame
$\rightarrow$ Assume all FFs are driven by a fault-free clock line.
$\rightarrow$ An input vector for the array is a sequence of $k$ input vectors for the synchronous circuit.

## Synchronous State m/c model



## Model for one time frame



- Since the circuit is same for every frame, we do not have to generate $n$ copies
- However, we should separately maintain signal values of each time frame


## Some observations

$\rightarrow C^{\prime}$ is a combinational circuit, so any combinational TG algorithm (D, PODEM, CPTG, etc.) can be applied
$\rightarrow$ A test vector $t$ for $C^{\prime}$, may specify Pl and $q$ values
$\rightarrow q$ values must be justified in previous timeframe
$\rightarrow t$ may not propagate an error to a PO but to a q+ variable
$\rightarrow$ Error must be propagated to next time frame
$\rightarrow$ In general, search process
$\rightarrow$ May span multiple time frames
$\rightarrow$ Going backward and forward in time

## Fault Propagation

$\rightarrow$ Target fault can be present in every time frame! $\rightarrow$ Error value ( D or $\mathrm{D}^{\prime}$ ) may propagate onto the faulty line itself

| Value propagated <br> onto line $l$ | Fault of line $l$ | Resulting value <br> of line $l$ |
| :---: | :---: | :---: |
| $D$ | $s-a-0$ | $D$ |
| $D$ | $s-a-1$ | 1 |
| $\bar{D}$ | $s-a-0$ | 0 |
| $\bar{D}$ | $s-a-1$ | $\bar{D}$ |

Figure 6.73 Result of a fault effect propagating to a faulty line

## TG from a Known Initial State

$r=1$
repeat
begin
build model with $r$ time frames
ignore the POs in the first $r-1$ frames
ignore the $q^{+}$outputs in the last frame
$q(1)=$ given initial state
if (test generation is successful) then return SUCCESS
/* no solution with frames */
$r=r+1$
end
until $r=f_{\text {max }}$
return FAHENRE

Once circuit is unrolled, we can use any of the test generation algorithm we studied for combinational circuits, such as D-alg(), PODEM, etc.

## Iterative Array Model



Ignore POs in
r-1 slices

## Example

$\rightarrow$ Assume $q_{1}=a_{2}=0$


## Time Frame



## Time Frame 1

- With $q_{1}=q_{2}=0$, fault is activated ( $D^{\prime}$ )
- With $I=1$, error is propagated to $q_{2}^{+}$but does not reach Z

- D-frontier $=\{\mathrm{G} 1, \mathrm{G} 3, \mathrm{G} 4\}$
- If G1 or G4 is chosen, then $\mathrm{I}=1$ gives $\mathrm{q}_{1}{ }^{+}=\mathrm{D}^{\prime}$ and $\mathrm{q}_{2}{ }^{+}=\mathrm{D}^{\prime}$
- If G3 is selected with $\mathrm{I}=0$ gives $\mathrm{q}_{1}{ }^{+}=0$ and $\mathrm{q}_{2}{ }^{+}=\mathrm{D}$

- D-frontier $=\{Z, G 1, G 2, G 3, G 4\}$
- With $\mathrm{I}=1$, we get $\mathrm{Z}=\mathrm{D}$, error propagated to a PO!
- Desired test sequence is $I=(1,1,1)$



## Generation of Self-initializing Test Sequences

```
r=1
p=0
repeat
    begin
        build model with p+r time frames
        ignore the POs in the first p+r-1 frames
        ignore the q}\mp@subsup{q}{}{+}\mathrm{ outputs in the last frame
        if (test generation is successful and every q input in the first frame has
            value }x\mathrm{ ) then return SUCCESS
        increment r or p
    end
until ( }r+p=\mp@subsup{f}{\mathrm{ max }}{}
return FAILURE
```


## Generation of Self-initializing Test Sequences

(a)


1. Activate fault in frame 1, and propagate it to PO using $r$ frames.
2. If $q(0)$ is not all $x$, justify $q(0)$ by backward propagation of $p$ frames.


## Example: Iterative Arrav: Detect Z s-a-0




$$
q^{+}=J \bar{q}+\bar{K} q
$$

## Example: Iterative Array: Detect Z s-a-0



